


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/668,550	CHANDRA ET AL.	
	Examiner	Art Unit	
	David E. Martinez	2182	

SEARCHED			
Class	Subclass	Date	Examiner
710	52,56,57	1/24/2006	DM

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East see attached	1/24/2006	DM
Inventor search eDan	1/24/2006	DM
Databases: US Patents, US PGPUBS, USOCR, EPO, Derwent, IBM_TDB.	1/24/2006	DM
Tanh Nguyen	1/24/2006	DM